

TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY
ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS

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Docket No 856063 678

REPLACEMENT SHEET

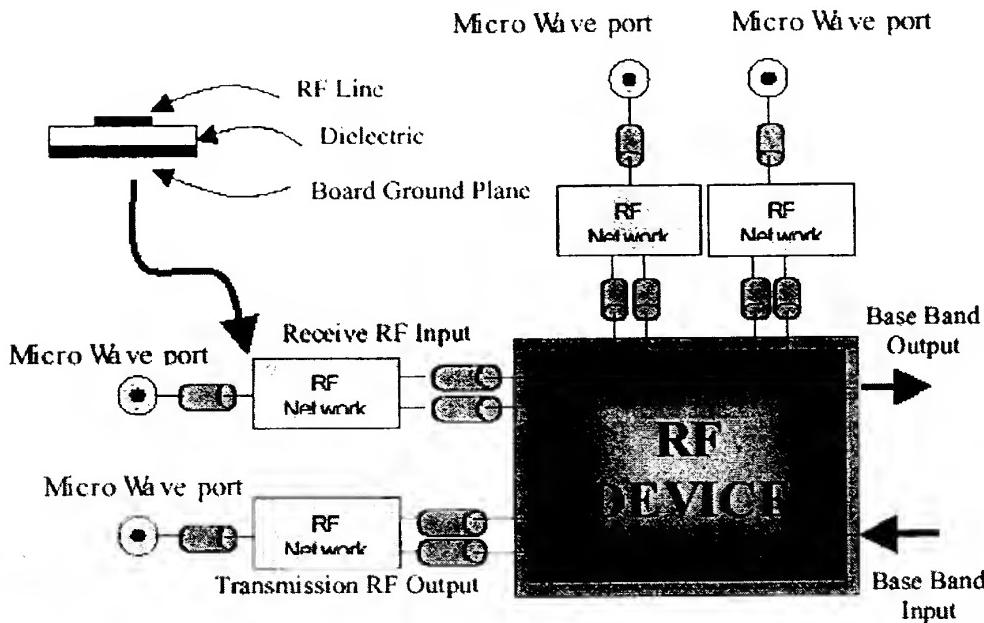


FIG. 1

(PRIOR ART)

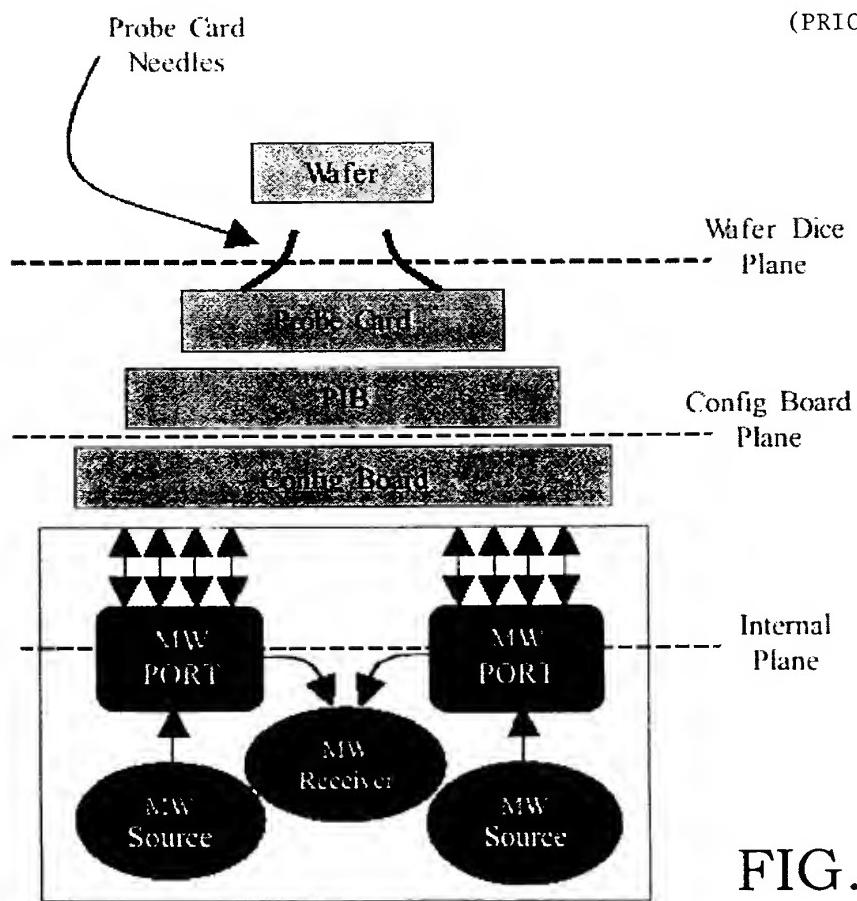


FIG. 2

(PRIOR ART)